

## ABSTRACT OF THE DISCLOSURE

A subscriber circuit and method for the internal functional testing of the subscriber circuit, wherein the circuit contains at least one signal processor, with a control device, an evaluation device and a device for generating test signals, at least one A/D converter and at least one high voltage part, a circuit arrangement for line monitoring of the subscriber circuit with a number of switches being provided in the at least one high voltage part, and wherein the control device is configured such that all the switches are closed in a test operating state.